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EXAMINER INITIAL										
JV	Dascher, David J., "Measuring Parasitic Capacitance and Inductance Using TDR", <u>Hewlett-Packard Journal</u> , April 1996, pp. 1-19.									
50√	MAXIUM, "Interfacing Ma	xim Laser Driv	vers with Laser	Diodes", May 2	2000, pp. 1-12.		·			
						 				
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